

Search Notes

Application/Control No.

10/628,327

Examiner

Nhan T. Tran

Applicant(s)/Patent under
Reexamination

IIDA, TAKAYUKI

Art Unit

2622

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
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